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CONTENTS

ECASIA 91 Preface i

Opening Speech iii

SECTION 1. TECHNIQUES DEVELOPMENT

Optimum Parameters for Combined Auger–Ionization Loss Coincidence Spectroscopy in the Reflection Mode 1
G. GERGELY

Some Practical Applications of Elastic Peak Electron Spectroscopy 5
C. JARDIN, G. GERGELY AND B. GRUZZA

Some Applications of High-energy, High-resolution Auger Electron Spectroscopy Using Bremsstrahlung Radiation 9
L. KÖVÉR, D. VARGA, I. CSERNY, J. TÓTH AND K. TÖKÉSI

SECTION 2. SYNCHROTRON APPLICATION

Improved Images with the Scanning Photoelectron Microscope at the National Synchrotron Light Source 17
H. ADE, C.-H. KO, E. D. JOHNSON AND E. ANDERSON

An Investigation of Surface Segregation in Magnetron-sputtered NbSi Using UPS and AES 23
P. K. HUCKNALL, C. G. H. WALKER, D. GREIG, J. A. D. MATTHEW, D. NORMAN AND J. TURTON

SECTION 3. POLYMERS

Redox Processes in Polyaniline Thin Film Studied by Optical Multichannel Analysis 27
M. C. BERNARD AND A. HUGOT-LE GOFF

The Intrinsic Redox States in Polypyrrole and Polyaniline: a Comparative Study by XPS 33
E. T. KANG, K. G. NEOH AND K. L. TAN

SECTION 4. DEPTH PROFILING

Ion-beam-induced Topography and Compositional Changes in Depth Profiling. (Invited paper) 39
G. CARTER AND M. J. NOBES

Alternative Model Multilayer Structures for Depth Profiling Studies 50
A. ZALAR, P. PANJAN, V. KRAŠEVEC AND S. HOFMANN

Effects of Rotation and Ion Incidence Angle on Sputter Depth Resolution in Thin Films of NiFe/Ta 55
M. M. HENNEBERG, D. J. POCKER AND M. A. PARKER

Quantitative AES Depth Profiling of Thin Oxide Films Grown on Stainless Steels and Aluminium 60
G. LORANG, J. L. XU AND J.-P. LANGERON

Caesium-ion-induced Auger Emission from Aluminium and Silicon 65
E. A. MAYDELL

Thickness Determination of Surface Oxides on Metal Powder by AES Depth Profiling 71
M. NORELL, L. NYBORG, T. TUNBERG AND I. OLEFJORD

Improved Depth Resolution of AES In-depth Profiling 77
A. BARNA, A. SULYOK AND M. MENYHARD

Study of Concentration–Depth Profiles in $CoSi_2$ Near-surface Layer after Ion Bombardment 80
S. S. VOJTUSIK, S. E. BORODYANSKY AND V. I. ZAPOROZHCHENCKO

A New Formalism for Angle-resolved X-ray Photoelectron Spectroscopy (ARXPS) and Auger Electron Spectroscopy (ARAES) of Non-crystalline Solids taking Elastic Electron Scattering into Account 83
W. S. M. WERNER AND H. STÖRI

SECTION 5. 3D-IMAGING, NANOPROBES

Prospects of X-ray Microscopy and X-ray Microtomography for Interface Studies 89
D. ERRE, X. THOMAS, D. MOUZE, J. M. PATAT, P. TREBBIA AND J. CAZAUX

Composition and Thickness of Surface Layer on Molybdenum Tips for Scanning Tunnelling Microscopy (STM) Studied by SEM/AES/(AR)XPS 93
W. LISOWSKI, A. H. J. van den BERG, L. J. HANEKAMP AND A. van SILFHOUT

SECTION 6. ADHESION

Characterization of Polymer Surfaces and Polymer–Metal Interfaces by Static Secondary Ion Mass Spectrometry. (Invited paper) 101
W. J. van OOIJ AND A. SABATA

A Comparative Study of the Influence of Surface Pretreatment on the Failure Characteristics of Adhesively Bonded Titanium 115
J. F. WATTS AND B. R. DEMPSTER

A Surface Study of the Chemical Pretreatment Before Coil Coating of Hot Dip Zinc-coated Steel 121
S. E. HÖRNSTRÖM, E. G. HEDLUND, H. KLANG, J.-O. NILSSON, M. BACKLUND AND P.-E. TEGEHALL

An *In Situ* XPS Study of the Formation of Aluminium–Polymer Interfaces 127
P. MARCUS, C. HINNEN, D. IMBERT AND J. M. SIFFRE

Thermal Stability and Degradation Mechanisms of Trialkylsilyl Surface Modifications on Silica Powder 133
J. W. SEVERIN, H. van der WEL, I. G. J. CAMPS, J. M. E. BAKEN AND J. M. J. VANKAN

Adsorption of Hydrogen Fluoride on Alumina 139
R. G. HAVERKAMP, J. B. METSON, M. M. HYLAND AND B. J. WELCH

Effect of the Nature of the Etchant on the Adhesion Strength of a Ti Alloy 145
L.GILA, M. MORRA, E. OCCHIELLO AND F. GARBASSI

Effects of Flame Treatment on Propylene–Ethylene Copolymer Surfaces 151
E. SHENG, I. SUTHERLAND, D. M. BREWIS AND R. J. HEATH

SECTION 7. DATA INTERPRETATION, QUANTIFICATION

Quantitative Studies of the Initial Oxidation Stages of FeCrNi Alloys using Factor Analysis and Least-squares Fitting Methods Applied to Low-energy AES Spectra 157
H. J. STEFFEN AND S. HOFMANN

Evaluation of Take-off-angle-dependent XPS for Determining the Thickness of Passivation Layers on Aluminium and Silicon 161
P. L. J. GUNTER, A. M. de JONG, J. W. NIEMANTSVERDRIET AND H. J. H. RHEITER

Enhancing the Interpretation of X-ray Photoelectron Spectra using Numerical Methods 165
W. F. STICKLE AND P. E. SOBOL

Background Correction in XPS: Comparison of Validity of Different Methods 171
S. TOUGAARD AND C. JANSSON

Maximum Entropy: a New Approach to Non-destructive Deconvolution of Depth Profiles from Angle-dependent XPS 175
G. C. SMITH AND A. K. LIVESEY

CONTENTS

Methods of Electron Spectra Processing Based on Solving the Transport Equation of Electron Motion in a Solid 181
S. BORODYANSKY

Quantitative Depth Profiling of Nitrogen-implanted Titanium by Use of Auger Electron Spectroscopy and Subsequent Target Factor Analysis 187
H. BUBERT AND A. MUCHA

Auger Backscattering Factor at Primary Beam Energies Above 10 keV 192
C. MERLET, O. JBARA, S. RONDOT AND J. CAZAUX

Preliminary Results on Multiple Angular Detection Auger Spectroscopy 197
J. CAZAUX, T. BARDOUX, D. MOUZE, J. M. PATAT, G. SALACE, X. THOMAS AND J. TOTH

Application of AQUA and QUAX to Matrix Corrections in AES and XPS 200
A. G. FITZGERALD, P. A. MOIR AND B. E. STOREY

Composition of Oxides and Nitrides from Line Shapes of Metal Core Level X-ray Photoelectron Spectra 205
L.GALÁN, P. PRIETO, C. MORANT, L. SORIANO, J. M. SANZ, E. ELIZALDE AND F. RUEDA

Reference Samples for Depth Profiling: Highly Accurate Calibration of Implanted Ion Dose by Neutron Activation Analysis 211
R. P. H. GARTEN, H. BUBERT AND L. PALMETSHOFER

Validity of Background Correction Algorithms Studied by Comparison with Theory of Synchrotron-radition-excited Core Levels and their Corresponding Auger Peak Intensities 217
C. JANSSON, H. S. HANSEN, C. JUNG, W. BRAUN AND S. TOUGAARD

Quantitative XPS Analysis of SiN_x(:H) Films Using Simple Methods without Sputtering 222
M. KAZUTA, N. SO, H. KASAMURA AND M. KUDO

Bethe Ionization Cross-sections: a Quantitative Survey on Calculating the Backscattering Factor in AES 227
C. L. LEE AND C. K. ONG

Investigation of Hydrogen Sensitivity of SIMS Method 232
F. PAVLYAK

Activities of the ASTM Committee E-42 on Surface Analysis 237
C. J. POWELL

The NIST X-ray Photoelectron Spectroscopy Database 241
J. R. RUMBLE JR, D. M. BICKHAM AND C. J. POWELL

VAMAS Surface Chemical Analysis—A Unifying Approach for the 1990s 247
M. P. SEAH

Evaporated and Implanted Reference Layers for Calibration in Surface Analysis 253
U. WÄTJEN, H. BAX AND P. RIETVELD

Correlation of the Emission of SIMS Cluster Ions with Composition and Structure from the $Al_{2-x}Cr_xO_3$ Mixed Oxide Series 259
N. M. REED AND J. C. VICKERMAN

High-energy LMM Auger Transitions 264
S. Z. WEISZ, M. GOMEZ, O. RESTO, A. MANY AND Y. GOLDSTEIN

Quantitative Analysis of Reflection Electron Energy-loss Spectra 269
F. YUBERO AND S. TOUGAARD

SECTION 8. RADIATION EFFECTS

Physico-chemical Modifications of Solid Surfaces by Interaction with Ion Beams. (Invited paper) 275
S. PIGNATARO

Chemical Changes in Titanate Surfaces Induced by Ar^+ Ion Bombardment 286
A. R. GONZÁLEZ-ELIPE, J. M. SANZ, A. FERNANDEZ, J. P. ESPINÓS AND G. MUNUERA

A Possible Solution to the Problem of Compositional Change with Ion-bombarded Oxides 291
I. BERTÓTI, R. KELLY, M. MOHAI AND A. TOTH

Characterization of Implanted Surfaces by Unenhanced Surface Raman Scattering 298
M. S. MATHUR AND J. S. C. McKEE

SECTION 9. MICROELECTRONICS, SUPERCONDUCTORS

Ultrafast Electron Dynamics at Semiconductor Surfaces and Interfaces Studied with Subpicosecond Laser Photoemission. (Invited paper) 301
R. HAIGHT, M. BAEUMLER, J. A. SILBERMAN AND P. D. KIRCHNER

Electromigration of Metallic Islands on Si(001) Surface 309
T. ICHINOKAWA, H. IIZUMI AND C. HAGINOYA

XPS Analysis of Ion-beam-induced Oxidation of Silicon Substrates 313
J. L. ALAY AND W. VANDERVORST

Auger Analysis of Ni/Au/Te and Au/Te Ohmic Contacts on n-GaAs 318
H. BENDER, K. WUYTS, J. WATTÉ AND R. E. SILVERANS

Development of a Hyperthermal Oxygen-atom Generator 325
G. B. HOFLUND, M. R. DAVIDSON AND R. A. OUTLAW

An AES Study of LPCVD Ta_2O_5 Films on Si 331
K. KAJIWARA, C. ISOBE AND M. SAITOH

Use of Si 2p X-ray Photoelectron Diffraction as a Test of Epitaxial Thin Film Growth by Si Evaporation on Si(001) 336
L. KUBLER, F. LUTZ, J. L. BISCHOFF AND D. BOLMONT

Silicon Ion Bombardment of Sb/Si Contacts 341
J. B. MALHERBE, K. P. WEIMER, E. FRIEDLAND, L. J. BREDELL AND M. FLETCHER

Al–Cu–Si/TiW Interface Reaction due to Thermal Treatments 347
Y. MISAWA AND Y. KOIKE

Oxidation in Preparation of Oxide Superconducting Films by MBE using NO_2 and O_3 Gases 353
H. NONAKA, T. SHIMIZU, S. HOSOKAWA, S. ICHIMURA AND K. ARAI

Electron-irradiation-induced Effects on High-T_c Superconductors Analysed by High-resolution Auger Electron Spectroscopy 358
E. W. SEIBT AND A. ZALAR

Oxidation of Metals by an Oxygen Ion Beam in the MBE Process 365
T. SHIMIZU, H. NONAKA AND K. ARAI

Dependence of Boron Axial Channelling in Silicon on Crystal Orientation 369
C. TIAN, S. GARA, G. HOBLER AND G. STINGEDER

Characterization of AlGaAs/GaAs Interfaces by EELS and High-resolution *Z*-Contrast Imaging in Scanning Transmission Electron Microscopy (STEM) 374
H. LAKNER, M. MAYWALD, L. J. BALK AND E. KUBALEK

SECTION 10. CORROSION

Characterization of Chromatized Hot-dip-galvanized Steel and 55% AlZn-coated Steel Using ESCA and AES 379
J.-O. NILSSON, S.-E. HÖRNSTRÖM, E. HEDLUND, H. KLANG AND K. UVDAL

A Cross-sectional TEM Study of Corrosion Initiation in Rapidly Solidified Mg-based Ribbons 386
T. J. WARNER, N. A. THORNE, G. NUSSBAUM AND W. M. STOBBS

XPS Studies of Oxide Layers on InP after Oxidation in the Presence of Ce^{4+} 393
C. DEBIEMME-CHOUVY, D. BALLUTAUD, J. L. SCULFORT AND A. ETCHEBERRY

Weathering of Wood and Protection by Chromium Studied by XPS 397
P. J. de LANGE, A. K. de KREEK, A. van LINDEN AND N. J. COENJAARTS

XPS Study of Passive Films Formed on Molybdenum-implanted Austenitic Stainless Steels 403
E. DE VITO AND P. MARCUS

XPS and AES Studies of Carbon Steel Polarized in Aqueous Molybdate Solutions 409
F.-M. PAN, Y.-L. LIN AND J.-C. OUNG

ESCA Study of the Oxidation of DHP Copper 414
L. PEDOCCHI, A. BILLI, E. MARINELLI, J. X. WU AND G. ROVIDA

SECTION 11. THIN FILMS AND COATINGS

Monte-Carlo Simulations of the Point-to-Point Resolution in Scanning Auger Microscopy and X-ray Micro-analysis of Thin Overlayers 419
E. VALAMONTES, A. G. NASSIOPOULOS AND N. GLEZOS

Surface Characterization and Electrochemical Behaviour of Nitrogen- and Carbon-implanted Titanium 423
N. HEIDE, B. SIEMENSMEYER AND J. W. SCHULTZE

Surface Precipitation of Graphite Layers on Carbon-doped Nickel and Their Stabilization Effect against Chemisorption and Initial Oxidation 430
D. FUJITA AND T. HOMMA

Correlation of Hydrogen Content with Properties of Oxidic Thin Films 435
C. R. OTTERMANN, K. BANGE, W. WAGNER, M. LAUBE AND F. RAUCH

Electron Energy Loss Spectroscopy (EELS) and Electron Spectroscopic Imaging (ESI) for the Localization of Titanium in Chrysotile Asbestos 439
P. A. BERGHMANS AND F. C. ADAMS

Spectroscopic Ellipsometry Characterization of Anodic Films on Aluminium Correlated with Transmission Electron Microscopy and Auger Electron Spectroscopy 445
J. DE LAET, H. TERRYN, J. VEREECKEN AND J. VANHELLEMONT

Study of the Phase Composition of Iron-containing Langmuir–Blodgett Layers Before and After Thermal and Chemical Treatment 450
W. MEISEL AND P. GÜTLICH

Surface and In-depth Chemical Characterization of Sputter-deposited Cr–Si–O Layers by XPS and AES Techniques 453
I. BERTÓTI, A. TÓTH, M. CZERMANN, M. MENYHÁRD, A. SULYOK AND E. ZSOLDOS

XPS Studies on Intermetallic Phases Formed in Al–Ni and Al–Mn Thin Films 457
I. BERTÓTI, M. MOHAI, A. CSANÁDY, P. B. BARNA AND H. BEREK

Prolonged Lifetime of Electrochromism of Amorphous WO_3–TiO_2 Thin Films 464
S. HASHIMOTO AND H. MATSUOKA

Oxidation of Gd Thin Films on Si Substrates via Grain Boundaries 469
G. MOLNÁR, G. PETÖ, E. KÓTAI, E. ZSOLDOS, J. GYULAI AND L. GUCZI

X-ray Photoelectron Spectroscopy of Low-temperature Anodic Silicon Oxides 473
L. GALÁN, I. MONTERO, F. RUEDA AND J. M. ALBELLA

Extended Energy Loss Fine Structure and X-ray Photoelectron Spectroscopy Studies of Clean and Oxidized Fe Thin Films on Polycrystalline Cu 478
S. DI NARDO, L. LOZZI, M. PASSACANTANDO, P. PICOZZI, S. SANTUCCI, M. DE CRESCENZI AND H. den DAAS

Multiple-angle Ellipsometric Study of the Interfacial Layer in Si–SiO_2 Structures 483
A. PANEVA AND A. SZEKERES

On the Interaction of Silica Xerogel Thin Films with Oxidized Aluminium or Phosphate Coatings on Steel 487
A. STOCH AND J. STOCH

SECTION 12. CATALYSIS

The Frontiers of Surface Structure Analysis. (Invited paper) 493
G. A. SOMORJAI

Use of XPS and Ar^+ Depth Profiling to Determine the Dispersion Degree of Ni in Ni/TiO_2 and Ni/SiO_2 Catalysts 508
J. P. ESPINÓS, A. R. GONZÁLEZ-ELIPE, A. FERNÁNDEZ AND G. MUNUERA

Copper Speciation by Analytical Electron Spectroscopies: Case of the Intercalation Phase $Cu_{0.5}V_2O_5 \cdot 0.5H_2O$ 513
C. MALITESTA, L. SABBATINI, L. TORSI, P. G. ZAMBONIN, D. BALLIVET-TKATCHENKO, J. GALY, J.-L. PARIZE AND J. M. SAVARIAULT

Changes Induced in the Surface Characteristics and Catalytic Activity of Amorphous Cu–Zr by Hydrogen Pretreatment 519
T. KATONA, Á. MOLNÁR, I. V. PERCZEL, CS. KOPASZ AND Z. HEGEDÜS

XPS and UPS of Pt Catalysts of Different Preparation 524
Z. PAÁL AND R. SCHLÖGL

Properties of Surface-modified Alumina Catalysts of COS Synthesis 529
A. AUROUX, A. GERVASINI, L. NÉMETH, G. GÁTI, I. S. PAP AND G. MINK

XPS Study on Barium-promoted Copper Chromite Catalysts 533
C. L. BIANCHI, M. G. CATTANIA AND V. RAGAINI

Characterization of Graphite-supported Platinum Catalysts by Electrochemical Methods and XPS 537
F. A. de BRUIJN, G. B. MARIN, J. W. NIEMANTSVERDRIET, W. H. M. VISSCHER AND J. A. R. van VEEN

XPS Study of Pumice-supported Palladium and Platinum Catalysts 543
A. M. VENEZIA, D. DUCA, M. A. FLORIANO, G. DEGANELLO AND A. ROSSI

Joint Use of XPS and Auger Techniques for the Identification of Chemical State of Copper in Spent Catalysts 548
A. GUERRERO-RUIZ, I. RODRÍGUEZ-RAMOS, G. J. SIRI AND J. L. G. FIERRO

Catalytic Oxidation of Mo by Caesium Oxides 553
L. SORIANO, J. F. TRIGO, L. GALÁN AND F. RUEDA

Characterization Study of Polycrystalline Tin Oxide Surfaces Before and After Reduction in CO 559
J. E. DRAWDY, G. B. HOFLUND, M. R. DAVIDSON, B. T. UPCHURCH AND D. R. SCHRYER

XPS Investigation on Co–Cu Mixed Oxide Catalysts 565
G. FIERRO, R. DRAGONE, G. MORETTI AND P. PORTA

Growth and Dissolution of a Surface Graphitic Carbon Monolayer on Nickel and Low-chromium Ni–Cr Alloys 572
G. HÖRZ AND H.-H. ANGERMANN

Application of Transmission Mössbauer Effect Spectroscopy to the Study of Electrocatalysis and Adsorption Phenomena at the Nickel Hydroxide Electrode 577
A. A. KAMNEV, B. B. EZHOV, V. RUSANOV AND V. ANGELOV

Novel Method for Studying the Kinetics of Surface Reactions at Submonolayer Exposures: Decomposition of Acetic Acid on Palladium Foil 581
J. KELLETER, G. SCHÜLL, C. D. KOHL, U. GRÜNER, A. KRAFT AND H. WOLLNIK

Fine Structure of Supported and Promoted Catalysts as Deduced from XPS Intensity Data 586
H. PRALIAUD, G. A. MARTIN, J. FENYVESI, I. SOMOGYI, G. VARSÁNYI AND G. MINK

New Entries in the XPS Fingerprint Database for the Characterization of Precipitated Cu–Zn–Al Oxide Catalysts 591
I. GROHMANN, B. PEPLINSKI AND W. UNGER

SECTION 13. METALLURGY

Applications of Surface-analytical Techniques to Aluminium Surfaces in Commercial Semifabricated and Finished Products. (Invited paper) 595
M. AMSTUTZ AND M. TEXTOR

Grain Boundary Segregation in [100] Symmetrical Tilt Bicrystals of an Fe–Si Alloy 601
S. HOFMANN, P. LEJČEK AND J. ADÁMEK

Surface Studies of Powder Metallurgical Stainless Steel 607
L. NYBORG, M. NORELL AND I. OLEFJORD

Estimation of the Grain Boundary Coverage of Segregated Impurities from the Kinetics of Free Surface Segregation 615
M. MENYHARD

The Improved MTCIP-1A (Modern Thermodynamic Calculation of Interface Properties—First Approximation) and its Application to the (Pt)Ni Surfaces 618
L. Z. MEZEY AND W. HOFER

Segregation in Some Nickel-based Hard-facing Alloys Prepared by Melt-spinning 623
S. HAMAR-THIBAULT, J. AJAO AND S. LEBAILI

SAM Investigations of the Segregation of Sulphur in Polycrystalline α-Iron 627
M. M. EISL, B. M. REICHL, S. D. BÖHMIG AND H. STÖRI

CONTENTS

On the Oxidation of γ'-Fe_4N_{1-x} Layers; Redistribution of Nitrogen 633
M. A. J. SOMERS, B. J. KOOI, W. G. SLOOF AND E. J. MITTEMEIJER

Application of Glow Discharge Optical Emission Spectroscopy to Diffusion Measurement of Copper in Ferritic and Austenitic Iron and Steels 638
S. SUZUKI, K. SUZUKI, F. KUROSAWA AND H. KOBAYASHI

Author Index 643